
Noise measurements in superparamagnetic tunnel junctions

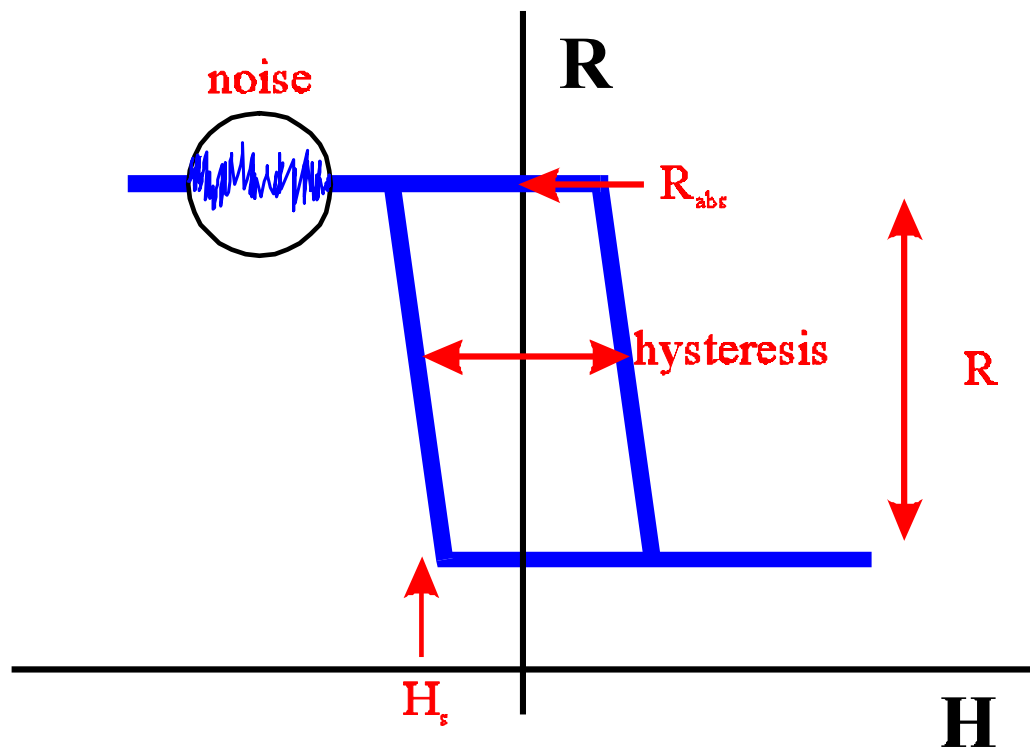
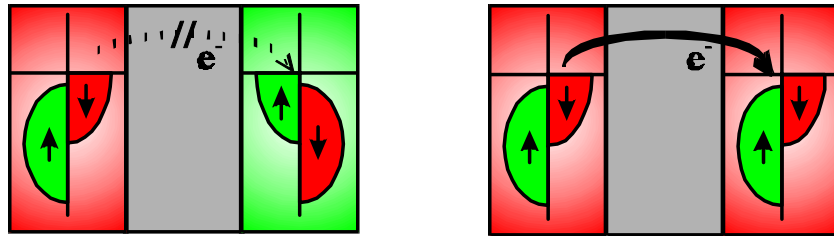
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Superparamagnetic tunnel junctions

Tunnel-magnetoresistance specifications



sensitivity

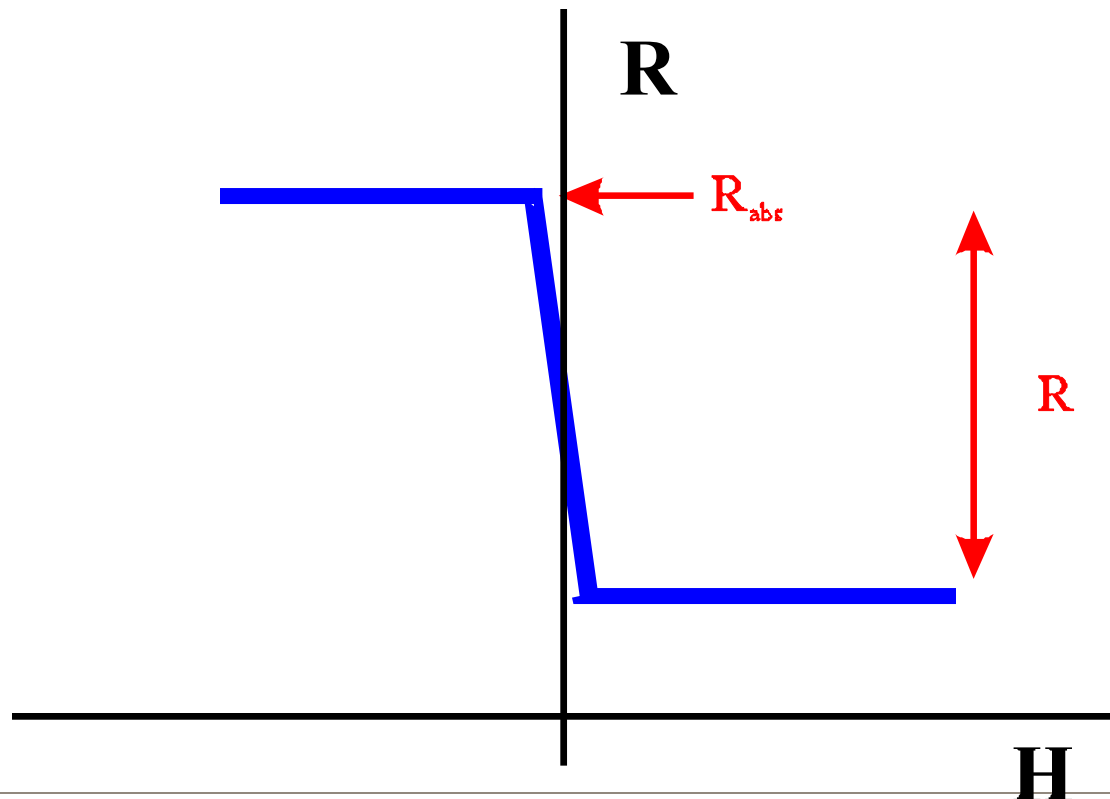
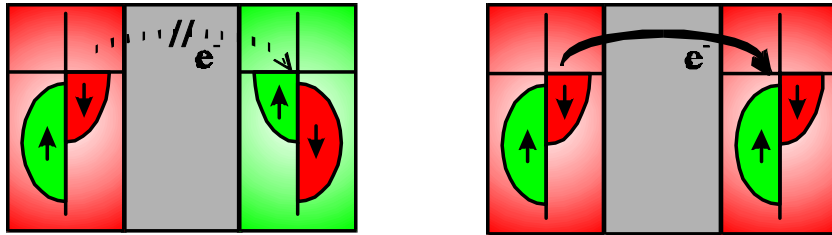
absolute resistance

hysteresis H_c

signal noise

Superparamagnetic tunnel junctions

Tunnel-magnetoresistance specifications



sensitivity

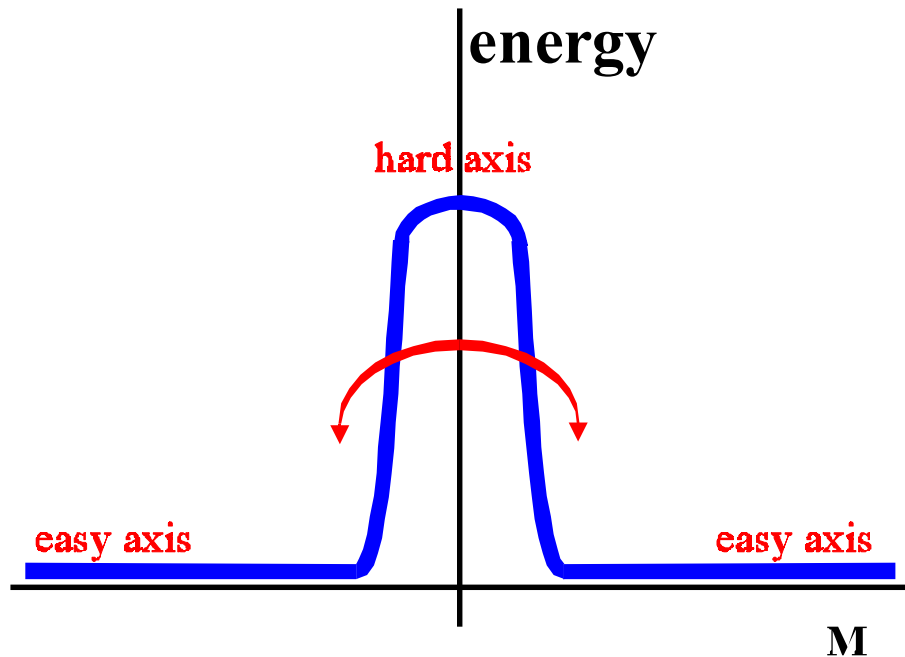
absolute resistance

hysteresis H_c

signal noise

Superparamagnetic tunnel junctions

Thermally unstable magnetization



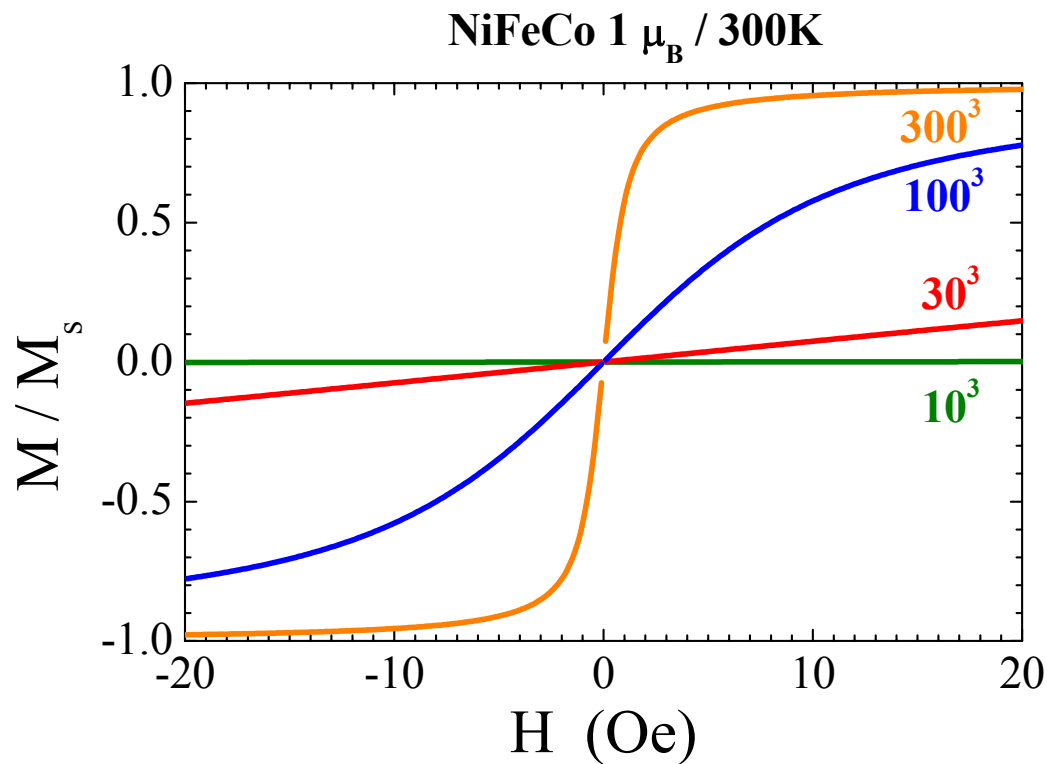
Arrhenius equation:

$$1/\tau = f_0 e^{-\Delta E/kT}$$

$$\Delta E = K_{\text{anisotropy}} * \text{Volume}$$

Superparamagnetic tunnel junctions

Magnetization of superparamagnetic particles



$$L(a) = \coth(a) - 1/a$$

$$a = M_s * Vol * H / kT$$

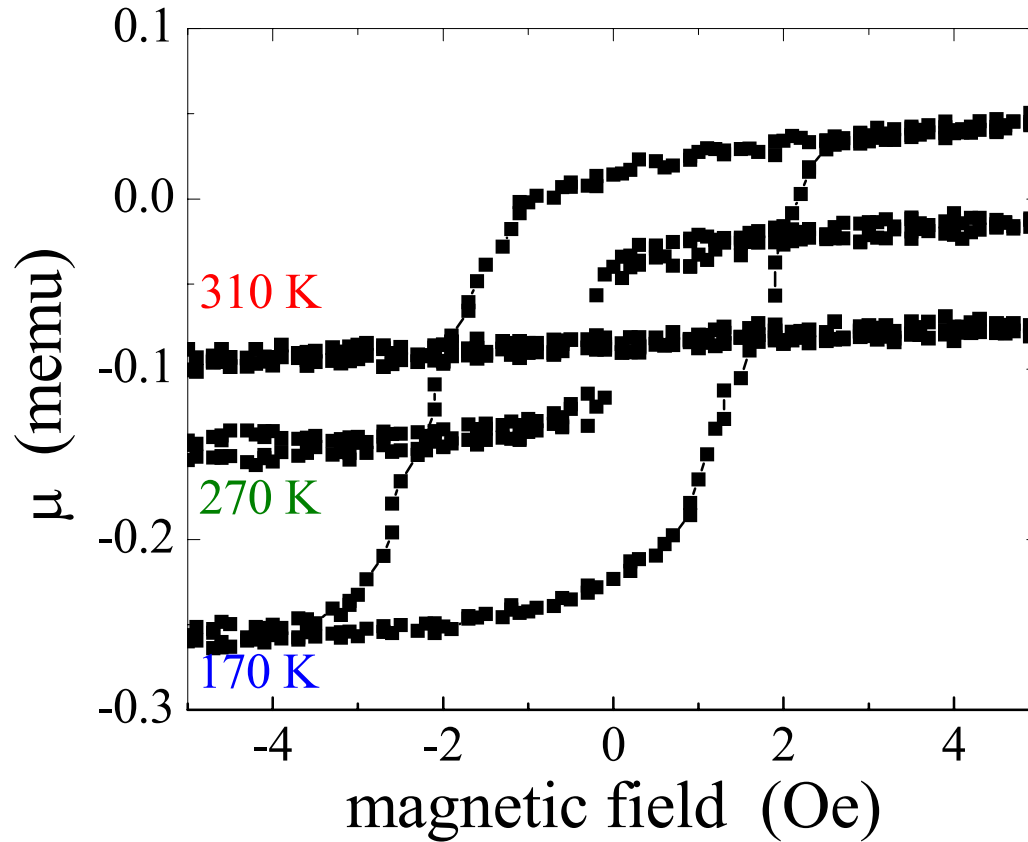
volume

magnetic field

temperature

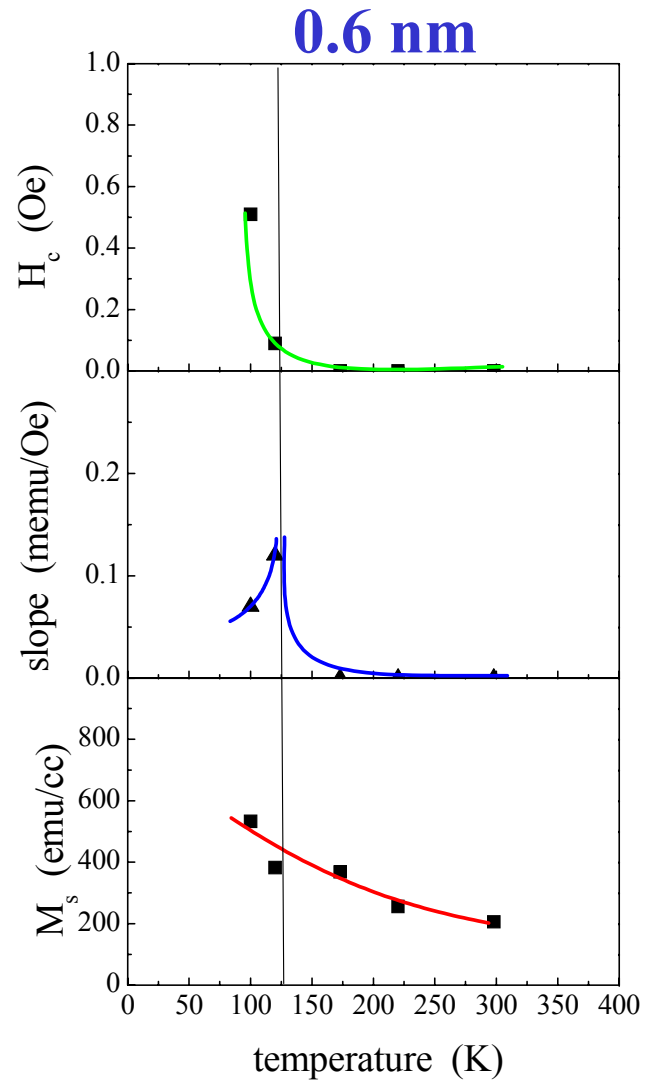
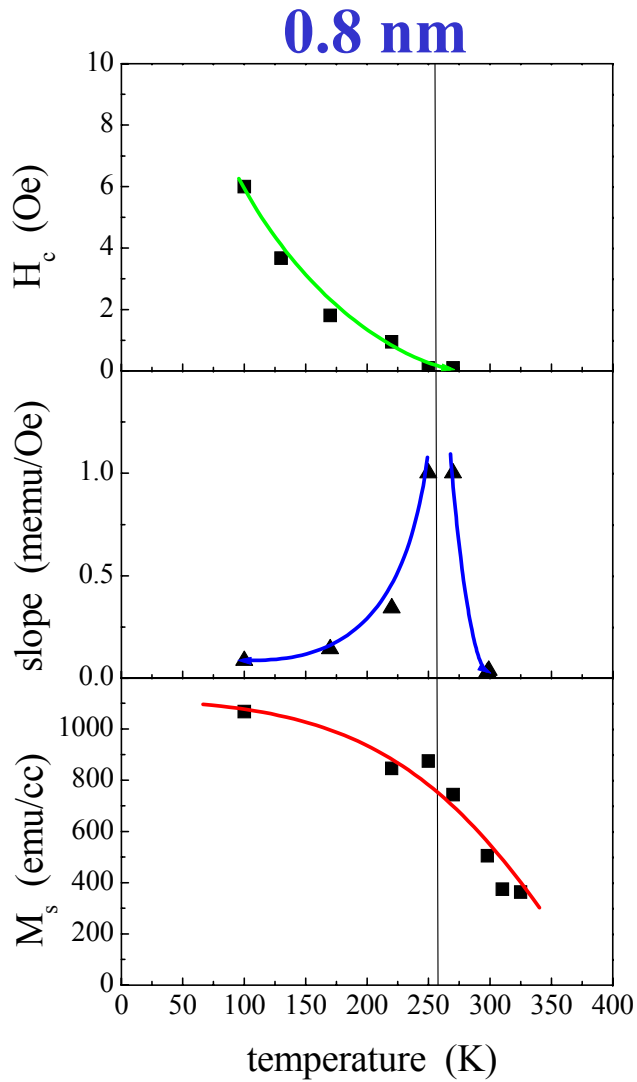
Superparamagnetic tunnel junctions

Cu / 0.8 nm NiFeCo / Cu



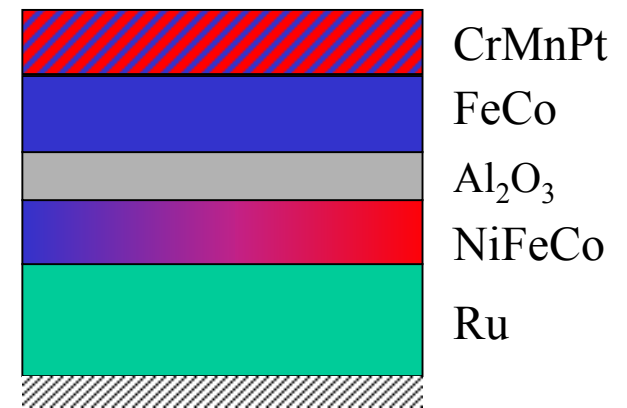
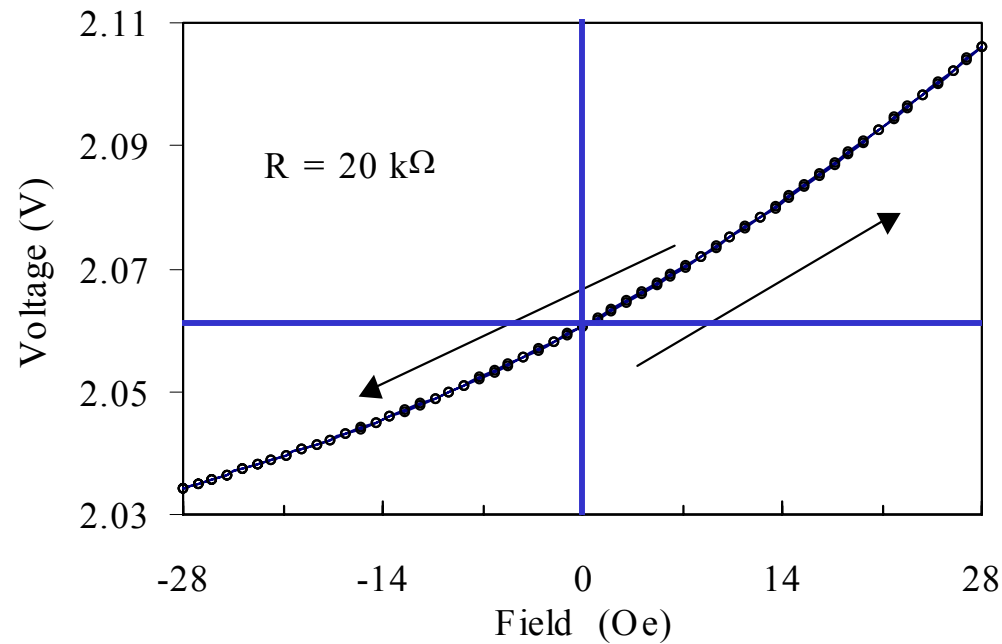
Superparamagnetic tunnel junctions

Cu / NiFeCo / Cu



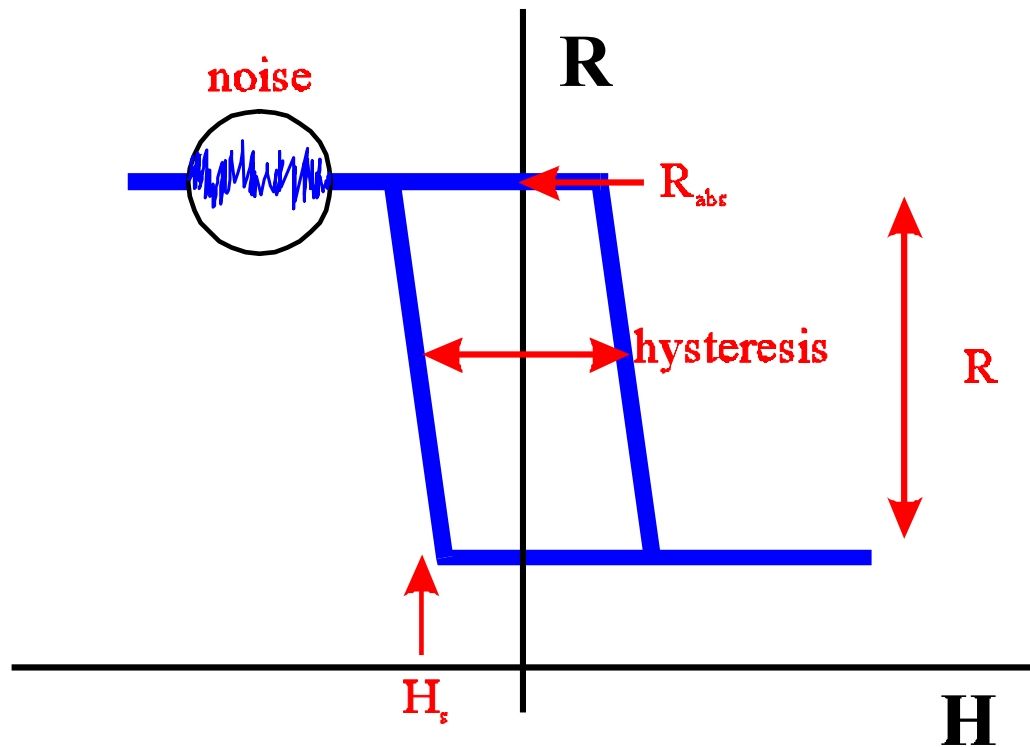
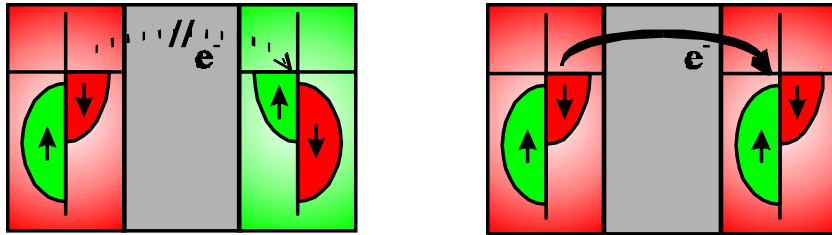
Superparamagnetic tunnel junctions

hysteresis-free magnetic field sensor



Superparamagnetic tunnel junctions

Tunnel-magnetoresistance specifications



sensitivity

absolute resistance

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signal noise

Noise measurements in superparamagnetic tunnel junctions

Electronic Noise

- Thermal noise

Johnson, Nyquist 1928

Is caused by the random, thermally induced, motion of conduction electrons.

$$S_t(f) = 4kTR \quad \text{V}^2/\text{Hz}$$

$$k = (1.38 \times 10^{-23} \text{ J/K})$$

$$T = 300\text{K}$$

$$R = 50 \text{ k}\Omega$$

$$S(f) \propto 10^{-16} \text{ V}^2/\text{Hz}$$

Noise measurements in superparamagnetic tunnel junctions

Electronic Noise

- Shot noise

Schottky 1918

Results from the random passage of individual charge carriers across a potential barrier.

$$S_i(f) = 2eI_{DC} \quad A^2/Hz$$

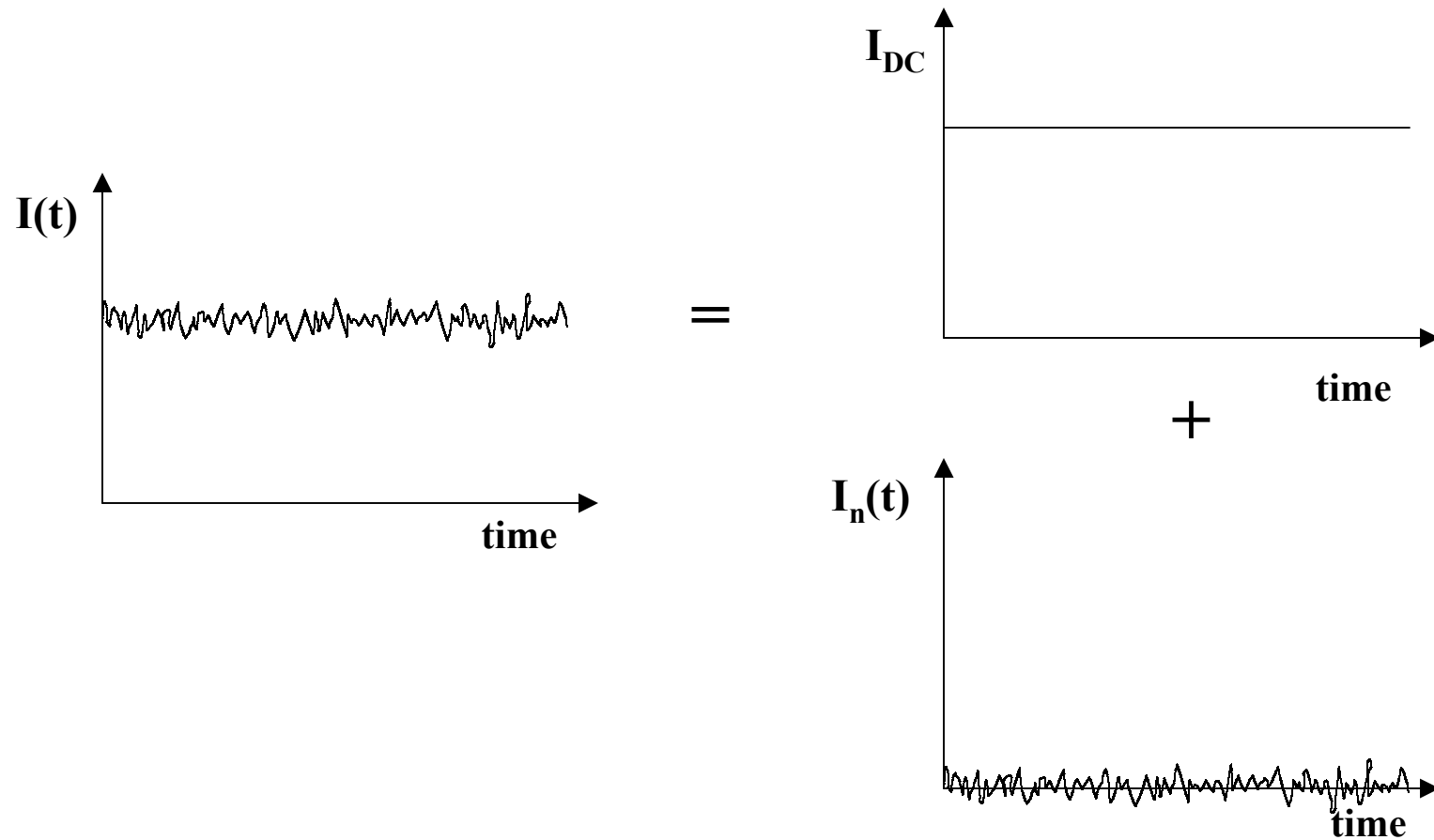
If $I(t)$ is the total current then :

$$I(t) = I_{DC} + I_n(t)$$

Noise measurements in superparamagnetic tunnel junctions

Electronic Noise

- Shot noise



Noise measurements in superparamagnetic tunnel junctions

Electronic Noise

- **Low frequency noise**

1/f or 'excess' noise

Appears as a fluctuation of the steady current flowing through a device.

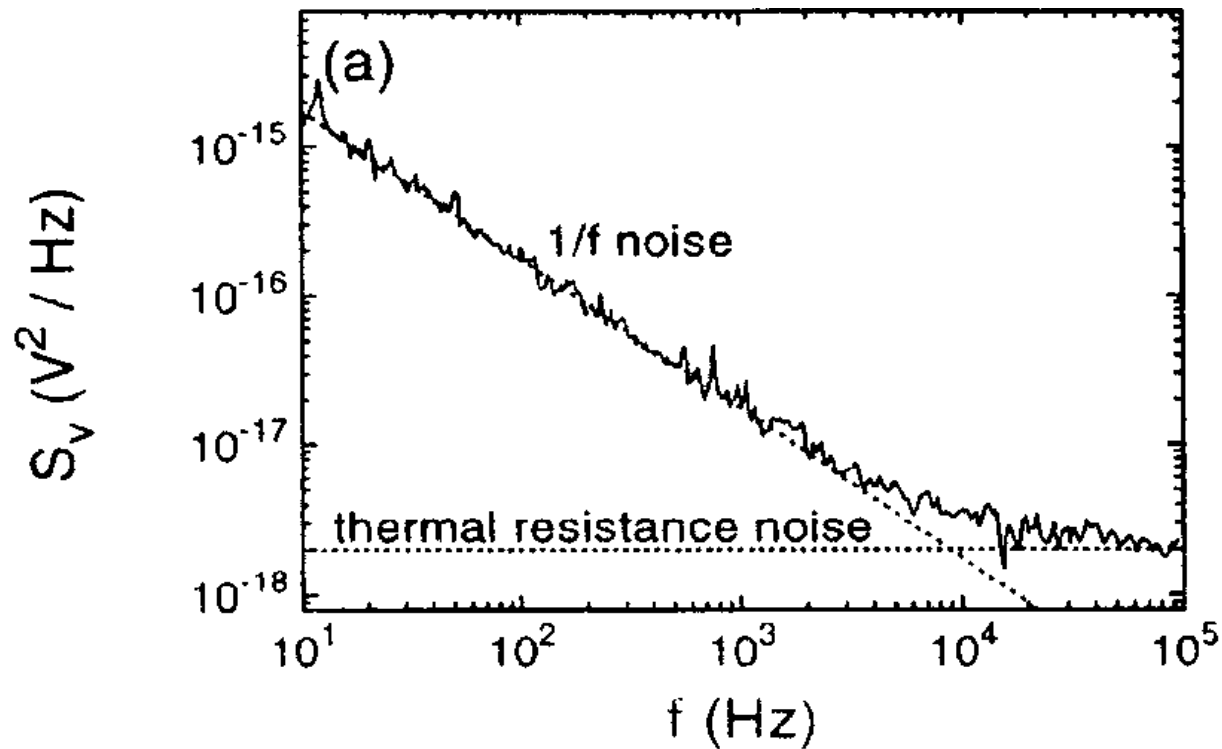
$$S_f(f) = K_f / f^\alpha \quad \text{V}^2/\text{Hz}$$

The index α is usually in the range 0.8 – 1.4

Noise measurements in superparamagnetic tunnel junctions

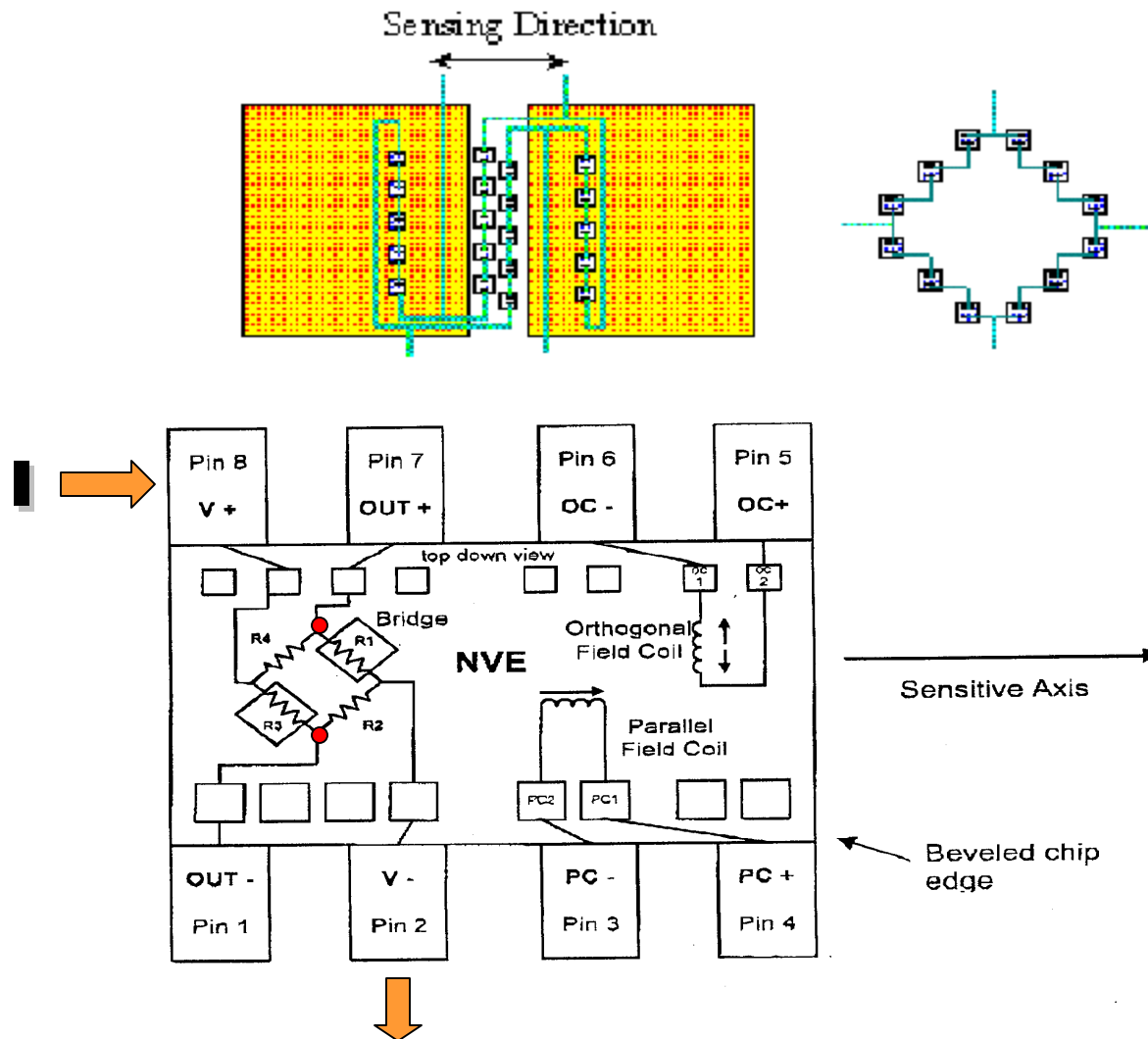
Electronic Noise

- Low frequency noise



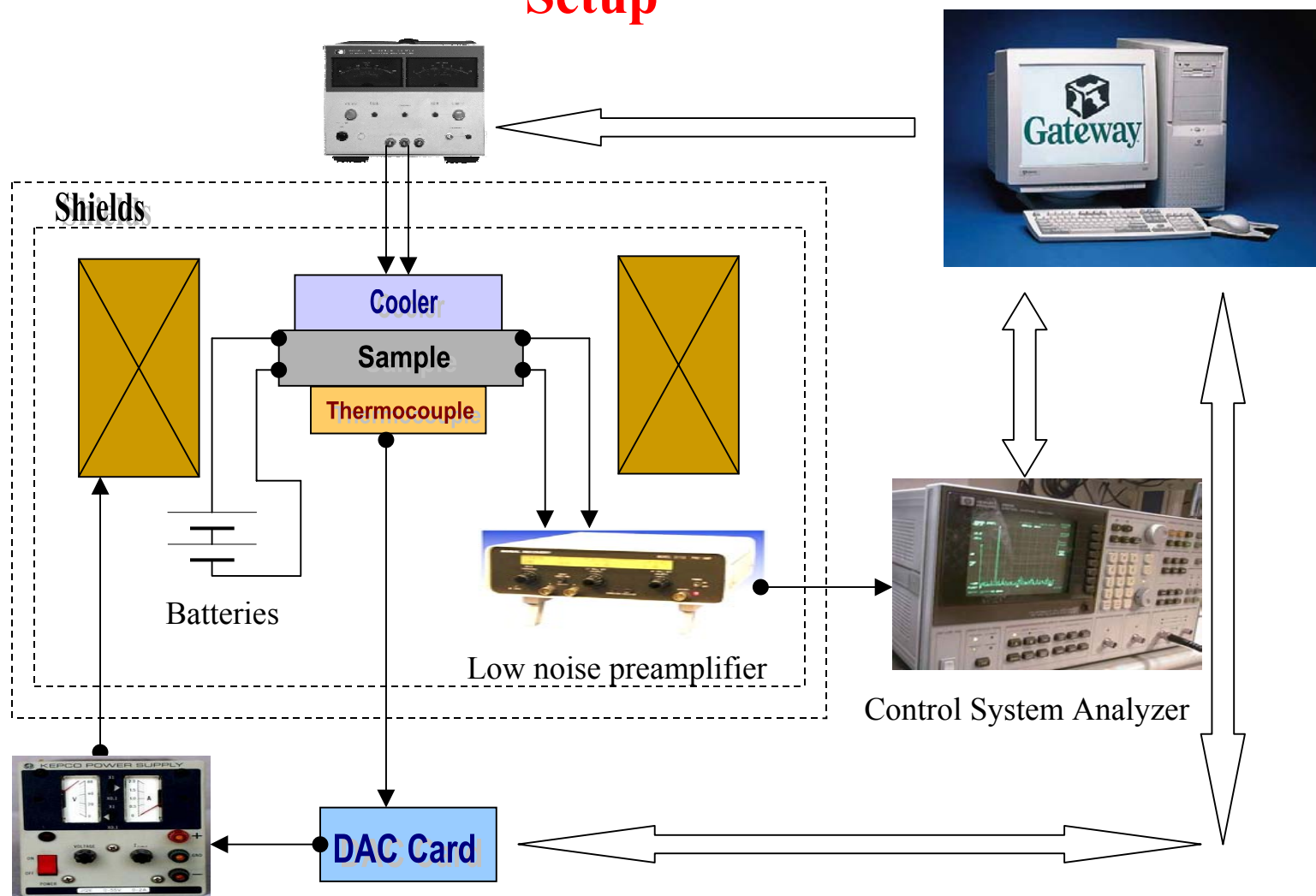
Superparamagnetic tunnel junctions

The SDT sensor



Noise measurements in superparamagnetic tunnel junctions

Setup



Noise measurements in superparamagnetic tunnel junctions

